

Notice of References Cited	Application/Control No. 10/573,630	Applicant(s)/Patent Under Reexamination OHISHI ET AL.	
	Examiner Dung V. Nguyen	Art Unit 3723	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 2004-183208	07-2004	Japan	Koike et al	B24C 1/00
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NON-PATENT DOCUMENTS

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